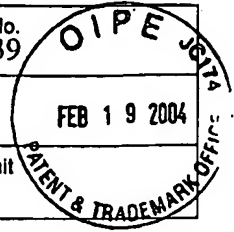


Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-126004	Application No. 10/647,539
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki et al.	
		Filing Date August 26, 2003	Group Art Unit 2814



U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
LP	AA	5,529,937	06/25/1996	Zhang et al.			07/20/1994
	AB	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
	AC	5,696,003	12/09/1997	Makita et al.			12/16/1994
	AD	5,821,562	10/13/1998	Makita et al.			05/30/1995
	AE	5,923,962	07/13/1999	Ohtani et al.			04/28/1995
	AF	6,093,937	07/25/2000	Yamazaki et al.			02/19/1997
	AG	6,285,042	09/04/2001	Ohtani et al.			09/12/1997
	AH	6,323,072	11/27/2001	Yamazaki et al.			05/15/2000
	AI	6,335,541	01/01/2002	Ohtani et al.			04/15/1996
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
LP	AL	0 651 431 A2	05/03/1995	EUROPE			IN ENGLISH	
	AM	1995-0004453	02/18/1995	KOREA			ABS	
	AN	1995-0012580	05/16/1995	KOREA			ABS	
	AO	1995-0021777	07/26/1995	KOREA			ABS	
	AP	1997-0063763	09/12/1997	KOREA			ABS	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature <i>Long Pham</i>	Date Considered <i>4/18/04</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
LP	AA	4,907,053	03/1990	Ohmi			
	AB	5,042,918	08/1991	Suzuki			
	AC	5,274,485	12/1993	Narita et al.			
	AD	5,294,821	03/1994	Iwamatsu			
	AE	5,359,219	10/1994	Hwang			
	AF	5,488,243	01/1996	Tsuruta et al.			
	AG	5,508,765	04/1996	Nakagawa et al.			
	AH	5,543,352	08/06/1996	Ohtani et al.			
	AI	5,608,232	03/04/1997	Yamazaki et al.			
	AJ	5,616,944	04/1977	Mizutani et al.			
	AK	5,639,698	06/17/1997	Yamazaki et al.			
	AL	5,643,801	07/01/1997	Ishihara et al.			
	AM	5,654,573	08/1977	Oashi et al.			
	AN	5,670,812	09/1997	Adler et al.			
	AO	5,843,225	12/01/1998	Takayama et al.			
	AP	5,882,960	06/16/1999	Zhang et al.			
	AQ	5,895,933	04/20/1999	Zhang et al.			
	AR	5,897,347	04/27/1999	Yamazaki et al.			
	AS	5,956,579	09/21/1999	Yamazaki et al.			
	AT	5,982,002	11/1999	Takasu et al.			
	AU	6,084,247	07/04/2000	Yamazaki et al.			
✓	AV	6,107,639	08/22/2000	Yamazaki et al.			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
LP	AW	06-232059	08/19/1994	JAPAN			Yes	
LP	AX	06-244103	09/02/1994	JAPAN			Abst.	

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Foreign Patent Documents or Published Foreign Patent Applications								
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							Yes	No
LP	AY	07-321339	12/08/1995	JAPAN			Abst.	
↓	BA	08-255916	10/1/1996	JAPAN			Abst.	

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
LP	BB	Takahashi, et al., "Oxide-semiconductor interface roughness and electrical properties of polycrystalline silicon thin-film transistors", Appl. Phys. Lett., Vol. 64, No. 17, pp. 2273-2275, April 25, 1994.
↓	BC	Cao, et al., "A Low Thermal Budget Polysilicon Thin Film Transistor Using Chemical Mechanical Polishing", Internal Display Research Conference, pp. 294-297, October 1994.
↓	BD	Shimokawa, et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, pp. 751-758, May 1988.
↓	BE	Wolf, S., et al. "Silicon Processing for the VLSI Era Volume 1: Process Technology", Lattice Press, Sunset Beach, CA, pp. 61-65, 335.
↓	BF	Wolf, S., "Silicon Processing for the VLSI Era Volume 3: The Submicron MOSFET", Sunset Beach, CA, p. 648.

Examiner Signature LONG PHAM	Date Considered 4/19/04
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Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
07977-126004Application No.
10/647,539Information Disclosure Statement
by Applicant

(Use several sheets if necessary)

Applicant
Shunpei Yamazaki et al.Filing Date
August 26, 2003

Group Art Unit

(37 CFR 1.98(b))

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
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LP	AL	08-255916	10/01/1996	JAPAN			Full	
	AM							
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4/19/04

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Substitute Disclosure Form (PTO-1449)